

INFULL (Indian (IN) Patents Full Text)

Subject Coverage	All patent-relevant areas of science and technology, i.e., all classes of the International Patent Classification		
File Type	Full Text		
Features	Thesauri	International Patent Classification (/IPC), Cooperative Patent Classification (/CPC), European Patent Classification (/EPC and /ICO)	
	Alerts (SDIs)	Weekly or monthly (weekly is the default)	
	CAS Registry Number [®] Identifiers	<input type="checkbox"/>	Page Images <input type="checkbox"/> STN [®] AnaVist [™] <input type="checkbox"/>
	Keep & Share	<input checked="" type="checkbox"/>	SLART <input checked="" type="checkbox"/> STN Easy [®] <input type="checkbox"/>
	Learning Database	<input type="checkbox"/>	Structures <input type="checkbox"/>
Record Content	<ul style="list-style-type: none"> • Full text of patent applications and granted patents in India from publication year 1912 onwards. • Records are available about a week after publication date with the complete content. • Records contain bibliographic data including patent applicant and inventor, patent, application, priority, and related application data, IPC, CPC, EPC and ICO classification codes, abstract, and full text of description and claims. • Abstracts are either original or taken from equivalent documents if available. If description and claims are not present in sufficient quality, they are taken from equivalent documents and indexed with DETD.EQ and/or CLM.EQ in the field availability (FA) index. • Numeric values of 55 physical and chemical properties are searchable in about 1800 unit variants in all full text fields. • Original application and publication numbers are indexed in the search fields application number, original (/APO) and patent number, original (/PNO). • Database records comprise all documents published for one application. • Family display formats from the INPADOCDB database up to 2004 are available. • Bibliography and full text have been created by Optical Character Recognition (OCR) software for many documents. A number of original documents are printed in poor quality and may cause misinterpretations of characters. Portions of the text may be incomplete. 		
File Size	<ul style="list-style-type: none"> • More than 0.53 million family records with more than 0.56 million publications (01/2016) • More than 0.13 million front page images from 1975 to present (01/2016) 		
Coverage	1912–present; between 1912 and 1994, only granted patents (kind code A1) are available		
Updates	Weekly		
Language	English		
Database Producer	LexisNexis Univentio BV Galileiweg 8 2333 BE Leiden The Netherlands Phone:(+31) 88-6390000 Email: customersupport@univentio.com Copyright Holder		

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Sources Patent applications and granted patents published by the Intellectual Property Office in India

- User Aids**
- Online Helps (HELP DIRECTORY lists all help messages available)
 - STNGUIDE
-

- Clusters**
- AEROTECH
 - ALLBIB
 - AUTHORS
 - CORPSOURCE
 - ENGINEERING
 - FULLTEXT
 - HPATENTS
 - PATENTS
 - PNTTEXT
- [STN Database Clusters](#) information (PDF)
NOTE: Clusters will be available after July 28, 2013.
-

Pricing Enter HELP COST at an arrow prompt.

Search and Display Field Codes

If multiple search terms are linked with and AND-operator, all terms are searched in the complete database record, i.e. in all publications referring to one application. For a search in a specific publication of the record, connect the search term and the patent kind code with the (L)-proximity operator, e.g., S BOREHOLE/AB, TI, CLM (L) INA/PK limits the search to Indian applications INA.

Fields that allow left truncation are indicated by an asterisk (*).

General Search Fields

Search Field Name	Search Code	Search Examples	Display Codes
Basic Index* (contains single words from title (TI), abstract (AB), detailed description (DETD), claims (CLM), and main claims (MCLM) fields)	None or /BI	S TRANSISTOR AND ELECTRODE S ACOUSTIC SENSOR S ?TRANSFER?	TI, AB, DETD, CLM, MCLM
Abstract *	/AB	S BOREHOLE/AB	AB
Accession Number	/AN	S 2011000109/AN	AN
Application Country (WIPO code and text)	/AC	S IN/AC	AI
Application Date (1)	/AD	S AD=JAN 2011	AI
Application Number (2)	/AP	S IN2010-CH1005/AP	AI
Application Number, Original	(or /APPS)		
Application Year (1)	/APO	S IN1005CHE2010/APO	APO
Claims *	/AY	S AY>=2000	AI
Cooperative Patent Classification (3)	/CLM	S DERIVATION/CLM	CLM
Cooperative Patent Classification, Action Date	/CPC	S C12N0009/CPC	CPC
Cooperative Patent Classification, Keyword	/CPC.ACD	S 20121113/CPC.ACD	CPC.TAB
Cooperative Patent Classification, Version	/CPC.KW	S C12N0009/CPC (S) I/CPC.KW	CPC.TAB
Data Entry Date	/CPC.VER	S 20130101/CPC.VER	CPC.TAB
Date Update Date	/DED	S 20120113/DED	DED
Document Type	/DUPD	S 20120124/DUPD	DUPD
(code and text)	/DT	S P/DT	DT
Entry Date (1)	(or /TC)	S PATENT/DT	
Entry Date of Full-text (1)	/ED	S ED=MAY 2013	ED
European Patent Classification (3)	/EDTX	S 20130526/EDTX	EDTX
EPC. Keyword	/EPC	S H02K0003-12/EPC	EPC
Field Availability	(or /ECLA)		
Graphic Image Size	/EPC.KW	S K23G200/06/EPC.KW	EPC
Graphic Image Type	/FA	S AB/FA	FA
International Patent Classification (ICM, ICS, IPCI, IPCR) (3)	/GIS	S 2016/GIS	GIS
International Patent Classification (ICM, ICS)	/GIT	S TIFF/GIT	GIT
ICO (in-computer-only) Classification (3)	/IPC	S A01B0001-10/IPC	ICM, ICS, IPCI, IPCR
ICO, Keyword	/IC	S A45D/IC	IC, ICM, ICS
Inventor	/ICO	S M07C0251-36/ICO	ICO
	/ICO.KW	S L01F3/04C5B60/ICO.KW	ICO
	/IN	S CHADIVE RAJA REDDY/IN	IN
	(or /AU)	S PRAJNAN CHAITAN?/IN	
Inventor, Country (WIPO code and text)	/IN.CNY	S IN/IN.CNY	IN, IN.CNY
IPC, Additional	/ICA	S C07C043-00/ICA	ICA
IPC, Initial	/IPCI	S B21B0001/IPCI	IPCI, IPC
IPC, Keyword Terms	/IPC.KW	S INITIAL/IPC.KW	IPC.TAB
IPC, Main	/ICM	S A63B021-00/ICM	ICM, IC
IPC, Reclassified	/IPCR	S B21D0007-08/IPCR	IPCR, IPC
IPC, Reform	/IPC.REF	S A01B0001-16/IPC.REF	IPC.TAB
IPC, Secondary	/ICS	S A41D027-04/ICS	ICS, IC
IPC, Version	/IPC.VER	S 7/IPC.VER	IPC.TAB
Language (code and text)	/LA	S EN/LA	LA

General Search Fields (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Language, Filing (code and text) Main Claim*	/LAF	S ENGLISH/LAF	LAF
Number of Claims (1)	/MCLM	S ?FRACTURE?/MCLM	MCLM
Number of Paragraphs in DETD (Detailed Description) (1)	/CLMN	S 5-7/CLMN	CLMN
Patent Applicant/Patentee (4)	/DETN	S DETN<10	DETN
Patent Applicant, Country	/PA (or /CS)	S ARCELOR MITTAL/PA	PA
Patent Country (WIPO code and text)	/PA.CNY	S IN/PA.CNY	PA, PA.CNY
Patent Information Publication Type	/PC	S IN/PC	PI
Patent Kind Code	/PIT	S INA APPLICATION/PIT	PIT
Patent Number (2)	/PK	S INA/PK	PI
Patent Number, Original	/PN (or /PATS)	S IN2000CH00043/PN	PI
Patent Number/Kind Code	/PNO	S IN10005DELNP2007/PNO	PNO
Physical Properties	/PNK	S IN2005CH00024 A/PNK	PI
Priority Country (WIPO code and text)	/PHP	S PHV/PHP (S) BUFFER/BI	KWIC
Priority Date (1)	/PRC	S IN/PRC	PRN
Priority Date, First (1)	/PRD	S INDIA/PRC	
Priority Number (2)	/PRDF	S PRD=MAY, 20 2003	PRN
Priority Number, Original	/PRN	S 20030520/PRD	
Priority Year (1)	/PRNO	S 20010614/PRDF	PRN
Priority Year, First (1)	/PRNF	S DE2004-202004000592/PRN	PRN
Publication Date (1)	/PRNO	S US10061642/PRNO	PRNO, PRAO
Publication Year (1)	/PRY	S 2003/PRY	PRN
Related Patent Country	/PRYF	S 2003-2004/PRYF	PRN
Related Application Number	/PD	S PD=MARCH-APRIL 2011	PI
Related Application Date (1)	/PY	S PY>2008 AND L1	PI
Related Application Year (1)	/RLC	S WO/RLC	RLI
Title (English)*	/RLN	S WO2005-JP24280/RLN	RLI
Update Date (1)	/RLD	S 20050330/RLD	RLI
	/RLY	S 2005/RLY	RLI
	/TI	S FLUID###/TI	TI
	/UP	S UP=JUNE 2013	UP

(1) Numeric search field that may be searched using numeric operators or ranges.

(2) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.

(3) An online thesaurus is available in this field.

(4) Search with implied (S) proximity is available in this field.

Super Search Fields

Enter a super search code to execute a search in one or more fields that may contain the desired information. Super search fields facilitate crossfile and multfile searching. EXPAND may not be used with super search fields. Use EXPAND with the individual field codes instead.

Search Field Name	Search Code	Fields Searched	Search Examples	Display Codes
Application Number Group	/APPS	AP, PRN	S IN2011-CH1006/APPS	AI, PRAI, APPS

Property Fields¹⁾

In INFULL a numeric search for a specific set of physical properties (/PHP) is available within the full text fields (TI, AB, DETD, and CLM). The numeric values are not displayed as single fields, but highlighted within the hit displays.

Use EXPAND/PHP to search for all available physical properties. A search with the respective field codes will be carried out in all database fields with English text. The /PHP index contains a complete list of codes and related text for all physical properties available for numeric search.

Field Code	Property	Unit	Symbol	Search Examples
/AOS	Amount of substance	Mol	mol	S 10 /AOS
/BIR	Bit Rate	Bit/Second	bit/s	S 330/BIR
/BIT	Stored Information	Bit	Bit	S BIT > 3 MEGABIT
/CAP	Capacitance	Farad	F	S 1-10 MF/CAP
/CDN	Current Density	Ampere/Square Meter	A/m ²	S CDN>10 A/M**2
/CMOL	Molarity, Molar Concentration	Mol/Liter	mol/L	S UREA/BI (S) 2/CMOL
/CON	Conductance	Siemens	S	S 1S-3/CON
/DB	Decibel	Decibel	dB	S DB>50
/DEG	Degree	Degree	°	S CYLINDER/BI (S) 45/DEG
/DEN	Density (Mass Concentration)	Kilogram/Cubic Meter	kg/m ³	S ANTIBODY/CLM (S) 5E-3-10E-3/DEN
/DEQ	Dose Equivalent	Sievert	Sv	S 2/DEQ
/DOS	Dosage	Milligram/Kilogram	mg/kg	S DOS>0.8
/DV	Viscosity, dynamic	Pascal * Second	Pa * s	S DV>5000
/ECD	Electric Charge Density	Coulomb/Square Meter	C/m ²	S ECD>10
/ECH	Electric Charge	Coulomb	C	S 2-3/ECH
/ECO	Electrical Conductivity	Siemens/Meter	S/m	S ECO>800 S/M (5A) WATER
/ELC	Electric Current	Ampere	A	S 1-10/ELC
/ELF	Electric Field	Volt/Meter	V/m	S 650-700/ELF
/ENE	Energy	Joule	J	S TORQUE (5A) 20 - 30 /ENE
/ERE	Electrical Resistivity	Ohm * Meter	Ohm * m	S ERE>2
/FOR	Force	Newton	N	S 50 N /FOR
/FRE	Frequency	Hertz	Hz	S OSCILLAT?/BI (S) 1- 3/FRE
/IU	International Unit	none	IU	S IU>1000 (P) ANTIBIOTIC
/KV	Viscosity, kinematic	Square Meter/Second	m ² /s	S SILICON?/BI (5A) 10E-5 M**2/S /KV
/LEN (or /SIZ)	Length, Size	Meter	m	S 1-4/LEN
/LUME	Luminous Emittance, Illuminance	Lux	lx	S 10-50/LUME
/LUMF	Luminous Flux	Lumen	Lm	S LUMF>1000
/LUMI	Luminous Intensity	Candela	cd	S LUMI<4
/M	Mass	Kilogram	kg	S ALLOY/BI (30A) 1E-10-1E-5/M
/MCH	Mass to Charge Ratio	none	m/z	S MCH=100
/MFD (or /MFS)	Magnetic Flux Density	Tesla	T	S MFD>102
/MFR (or /MFL)	Mass Flow Rate	Kilogram/Second	kg/s	S MFR<0.1
/MM	Molar Mass	Gram/Mol	g/mol	S 2000-3000 G/MOL/MM
/MOLS	Molality of Substance	Mol/Kilogram	mol/kg	S 01.-10 MOL/KG/MOLS
/MVR	Melt Volume Rate	none	g/10 min	S 3/MVR
/NUC	Nutrition Content	none	g/100 kcal	S NUC<100 (P) NUTRIENT
/PER	Percent	none	%	S POLYMER?/AB (5A) 4/PER
/PERA	(Proportionality) Permittivity, Absolute	Farad/Meter	F/m	S 3/PERA

Property Fields₁₎ (cont'd)

Field Code	Property	Unit	Symbol	Search Examples
/PHV /POW	pH Value Power	pH Watt	pH W	S 7.4-7.6/PHV S LIGHT/BI (S) ENERGY/BI (S) 350 WATT/POW
/PRES (or /P)	Pressure	Pascal	Pa	S (VACUUM (5A) DISTILL?)/BI (S) 1000-1100/PRES
/RAD	Radioactivity	Becquerel	Bq	S RAD/PHP
/RES	Electrical Resistance	Ohm	Ohm	S SENSOR /BI (S) 10- 100/RES
/RSP	Rotational Speed	Revolution/Minute	rpm	S 2-100/RSP (S) MACHINE/AB
/SAR	Area /Surface Area	Square Meter	m ²	S (COATING? OR FOIL?)/BI (S) 10- 100/SAR
/SOL	Solubility	Gram/100 gram	g/100 g	S SOL>20 (10W) WATER
/STSC	Surface Tension	Joule /Square Meter	J/m ²	S 60 J/M**2/STSC
/TCO	Thermal Conductivity	Watt/Meter * Kelvin	W/m * K	S 1/TCO (S) HEAT?
/TEMP (or /T)	Temperature	Kelvin	K	S (REACTION? (10A) ENZYM?) (S) 5/TEMP
/TIM	Time	Second	s	S ?INCUB?/BI (10A) 10-50/TIM
/VEL (or /V)	Velocity	Meter per Second	m/s	S REDUC?/BI (S) 1E-3-5E-3/VEL
/VELA	Velocity, angular	Radian/Second	rad/s	S VELA>10
/VLR	Volumetric Flow Rate	Cubic Meter/Second	m ³ /s	S 1-2/VLR (5A) POWDER
/VOL	Volume	Cubic Meter	m ³	S 1E-8-2E-8/VOL.EX
/VOLT	Voltage	Volt	V	S POTENTIAL/CLM (10A) 5E-3 V <VOLT<7E-3 V

1) Exponential format is recommended for the search of particularly high or low values, e.g. 1.8E+7 or 1.8E7 (for 18000000) or 9.2E-8 (for 0.000000092).

International Patent Classification (/IPC) Thesaurus

The classifications, validity and catchwords for the main headings and subheadings from the current (8th) edition of the WIPO International Patent Classification (IPC) manual are available. The classifications from the previous editions (1-7) are also available as separate thesauri. To EXPAND and SEARCH in the thesauri for editions 1–7, use the field code followed by the edition number, e.g., /IPC2, for the 2nd edition. Catchwords are included only in the thesauri for the 8th, 7th, 6th, and 5th editions.

Code	Content	Examples
ADVANCED (ADV)	Advanced Codes for the Core Level IPC Code	E A61K0006-06+ADVANCED/IPC
ALL	All Associated Terms (BT, SELF, NT, RT)	E C01C003-00+ALL/IPC
BRO (MAN)	Complete Class	E C01C+BRO/IPC
BT	Broader Term (BT, SELF)	E C01F001-00+BT/IPC
CORE (COR)	Core Codes for the Advanced Level IPC Code	E G08C0019-22+CORE/IPC
ED	Complete title of the SELF term and IPC manual edition	E C01F001-00+ED/IPC
HIE	Hierarchy Term (Broader and Narrower Term) (BT, SELF, NT)	E C01B003-00+HIE/IPC
INDEX	Complete title of the SELF term	E C01F001-00+INDEX/IPC
KT	Keyword Term (catchwords) (SELF, KT)	E CYANOGEN+KT/IPC
NEXT	Next Classification	E C01C001-00+NEXT5/IPC
NT	Narrower Terms (SELF, NT)	E C01C+NT/IPC
PREV	Previous Classification	E C01C001-12+PREV10/IPC
RT (SIB)	Related Terms (SELF, RT)	E C01C003-20+RT/IPC
TI	Complete Title of the SELF Term and Broader Terms (BT, SELF)	E C01F001-00+TI/IPC

ECLA (/EPC) and ICO Thesauri

This thesaurus is available in the /EPC search field (for ECLA codes) and /ICO search field (for 'in-computer-only' codes). All relationship codes can be used with both the EXPAND and SEARCH commands.

Relationship Code	Content	Search Examples
ALL AUTO (1) BT CODE DEF HIE KT MAX NEXT NEXT(n) NT PREV PREV(n) TI	All usually required terms (BT, SELF, CODE, DEF) Automatic relationship (BT, SELF, CODE, DEF) Broader terms (BT, SELF) Classification Code (SELF, CODE) Definition (SELF, DEF) Hierarchy terms (all broader and narrower terms) (BT, SELF, DEF, NT) Keyword terms (SELF, KT) All associated terms Next classification within the same class (SELF, NEXT) Next n classification within the same class Narrower terms Previous Code within the same class (SELF, PREV) Previous n classifications within the same class Complete Title of the SELF Term and Broader Terms (BT, SELF)	E C12M0001-34H2+ALL/EPC E G01N0033-50D4 +AUTO/EPC E G01N0033-50D4 +BT/EPC E SCRAPER BIASING MEANS+CODE/EPC E B65G0045-16+DEF/EPC E A01C0001-06+HIE/EPC E LASER+KT/EPC E G01N0033-50D4+MAX/EPC E A01C0001-06+NEXT/EPC E A01C0001-06+NEXT3/EPC E G05B0019-10+NT/EPC E G05B0019-10+PREV/EPC E G05B0019-10+PREV2/EPC E G05B0019-10+TI/EPC

(1) Automatic Relationship is SET OFF. In case of SET REL ON, the result of EXPAND or SEARCH without any relationship code is the same as described for AUTO.

CPC Thesaurus

This thesaurus is available in the /CPC search field. All relationship codes can be used with both the EXPAND and SEARCH commands.

Relationship Code	Content	Search Examples
ALL AUTO (1) BT CODE DEF HIE KT MAX NEXT NEXT(n) NT PREV PREV(n) TI	All usually required terms (BT, SELF, CODE, DEF) Automatic relationship (BT, SELF, CODE, DEF) Broader terms (BT, SELF) Classification Code (SELF, CODE) Definition (SELF, DEF) Hierarchy terms (all broader and narrower terms) (BT, SELF, DEF, NT) Keyword terms (SELF, KT) All associated terms Next classification within the same class (SELF, NEXT) Next n classification within the same class Narrower terms Previous Code within the same class (SELF, PREV) Previous n classifications within the same class Complete Title of SELF Term and Broader Terms (BT, SELF)	E A61K0031-4375+ALL/CPC E C07D0473-40+AUTO/CPC E C12N0009-6464+BT/CPC E CARTRIDGES+CODE/CPC E B65G0045-16+DEF/CPC E F02M0031-047+HIE/CPC E LASER+KT/CPC E G01R0022-066+MAX/CPC E A01N0041-04+NEXT/CPC E A01N0041-04+NEXT3/CPC E C07D0473-40+NT/CPC E F05C2253-16+PREV/CPC E F05C2253-16+PREV2/CPC E F05B2250-313+TI/CPC

INFULL**DISPLAY and PRINT Formats**

Any combination of formats may be used to display or print answers. Multiple codes must be separated by spaces or commas, e.g., D L1 1-5 TI PA. The fields are displayed or printed in the order requested.

The information of the latest publication is displayed by default. To display the content for all levels of the record you can combine all display fields and formats with the qualifier .M except FA, FAM, CFAM, SCAN, and TRIAL.

For displaying a particular publication of a database record, you can simply add for certain display field the kind code to the appropriate display format, e.g. ALL.A. Fields that allow this are indicated by a number (3).

Hit-term highlighting is available for all fields. Highlighting must be ON during SEARCH to use the HIT, KWIC, and OCC formats.

The default display format is STD.M, i.e., all publication levels of one family in the STD format.

Format	Content	Examples
AB (ABS)	Abstract	D TI AB 1-5
AI (AP) (1)	Application Information	D AI
AN	Accession Number	D L3 AN
APO	Application Number, Original	D APO
CLM (3)	Claims	D CLM
CLMN (2)	Number of Claims	D CLMN
CPC	Cooperative Patent Classification	D CPC
DED	Data Entry Date	D DED
DETD (3)	Detailed Description	D DETD
DETN (2)	Number of Paragraphs in DETD	D DETN
DT (TC)	Document Type	D DT
DUPD	Data Update Data	D DUPD
ED	Entry Date	D ED
EDTX	Entry Date of Full-text	D EDTX
EPC	European Patent Classification	D EPC
FA	Field Availability (for all publication levels)	D FA
GI	Graphic Image	D GI
GIS (2)	Graphic Image, Size	D GIS
GIT (2)	Graphic Image, Type	D GIT
IC	IPC (format contains ICM, ICS)	D IC
ICA	IPC, Additional	D ICA
ICM	IPC, Main	D IC
ICO	ICO (in-computer-only) Classification	D ICO
ICS	IPC, Secondary	D ICS
IN (AU)	Inventor (in English)	D IN
IN.CNY	Inventor, Country	D IN.CNY
IPCI	IPC, Initial	D IPCI
IPCR	IPC, Reclassified	D IPCR
LA	Language	D LA
LAF	Language of Filing	D LAF
MCLM (3)	Main Claim	D MCLM
PA (CS)	Patent Applicant/Patentee (in English)	D PA
PA.CNY	Patent Applicant, Country	D PA.CNY
PI (PN, PATS) (1)	Patent Information	D PI
PIT	Patent Information Publication Type	D PIT
PNO	Patent Number, Original Format	D PNO
PRN (PRAI) (1,5)	Priority Information	D PRN
PRNO (PRAO) (2)	Priority Number, Original Format	D PRNO
RLI (RLN)	Related Patent Information	D RLI
TI	Title	D TI
UP	Update Date	D UP
ALL (1)	AN, DED, DUPD, ED, EDTX, UP, TI, IN, IN.CNY, PA, PA.CNY, LAF, LA, DT, PIT, PI, AI, RLI, PRAI, IPC, CPC, EPC, ICO, AB, DETD, CLM	D ALL
ALLG (1)	ALL, plus graphic image	D ALLG
IALL (1)	ALL, indented with text labels	D IALL
IALLG (1)	IALL, plus graphic image	D IALLG
DALL (1)	ALL, delimited for post processing	D DALL

DISPLAY and PRINT Formats (cont'd)

Format	Content	Examples
APPS (1) BIB (1)	AI, RLN, PRAI AN, DED, DUPD, ED, EDTX, UP, TI, IN, IN.CNY, PA, PA.CNY, LAF, LA, DT, PIT, PI, AI, RLI, PRAI	D APPS D BIB
BIBG (1) IBIB (1) IBIBG (1)	BIB, plus graphic image BIB, indented with text labels IBIB, plus graphic image	D BIBG D IBIB D IBIBG
CPC.TAB BRIEF (1)	CPC, CPC.KW, CPC.VER, CPC.ACD in tabular version AN, DED, DUPD, ED, EDTX, UP, TI, IN, IN.CNY, PA, PA.CNY, LAF, LA, DT, PIT, PI, AI, RLI, PRAI, IPC, CPC, EPC, ICO, AB, MCLM	D BRIEF
BRIEFG (1) IBRIEF (1) IBRIEFG (1)	BRIEF, plus graphic image BRIEF, indented with text labels IBRIEF, plus graphic image	D BRIEFG D IBRIEF D IBRIEFG
FAM (1) CFAM (1)	AN, table of patent family information (from INPADOCDB) AN, Condensed family format (from INPADOCDB)	D FAM D CFAM
IND IPC IPC.TAB	ED, IPC (ICM, ICS, IPCI, IPCR), CPC, EPC, ICO International Patent Classification (ICM, ICS, IPCI, IPCR) IPC, IPC.KW, IPC.VER, IPC.ACD in tabular version	D IND D IPC D IPC.TAB
MAX (ALL.M) (1)	AN, DED, DUPD, ED, EDTX, UP, TI, IN, IN.CNY, PA, PA.CNY, LAF, LA, DT, PIT, PI, AI, RLI, PRAI, IPC, CPC, EPC, ICO, AB, DETD, CLM, FA for all levels of publication	D MAX
MAXG (ALLG.M) (1) IMAX (IALL.M) (1) IMAXG (IALLG.M) (1)	MAX, plus graphic image MAX, indented with text labels IMAX, plus graphic image	D MAXG D IMAX D IMAXG
SCAN (4) STD (1)	TI (random display without answer numbers) AN, DED, DUPD, ED, EDTX, UP, TI, IN, IN.CNY, PA, PA.CNY, LAF, LA, DT, PIT, PI, AI, RLI, PRAI, IPC, CPC, EPC, ICO (STD.M is default)	D SCAN D STD
STDG (1) ISTD (1) ISTDG (1)	STD, plus graphic image STD, indented with text labels ISTD, plus graphic image	D STDG D ISTD D ISTDG
TRIAL (TRI, SAM, SAMPLE, FREE) TX	ED, EDTX, UP, TI, FA, DETN, CLMN DETD, CLM	D TRIAL D TX
HIT KWIC OCC	Hit term(s) and field(s) Up to 50 words before and after hit term(s) (KeyWord-In-Context) Number of occurrences of hit term(s) and field(s) in which they occur	D HIT D KWIC D OCC

- (1) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.
- (2) Custom display only.
- (3) You can combine this display field with the qualifier .PK (Patent Kind Code) to display the content for a certain publication level of a record, e.g. CLM.B2.
- (4) SCAN must be specified on the command line, i.e., D SCAN or DISPLAY SCAN.
- (5) If priority information is not available for a certain document, this information is taken from the application information of this document and marked with an asterisk (*).

INFULL**SELECT, ANALYZE, and SORT Fields**

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

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The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

You can combine all fields except FA with the qualifier .M to SELECT/ANALYZE the content of all publication levels.

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Abstract	AB	Y	Y
Accession Number	AN	Y	Y
Application Country	AC	Y	Y
Application Date	AD	Y	Y
Application Information	AI (AP, APPS)	Y (2)	Y
Application Number, Original	APO	Y	Y
Application Year	AY	Y	Y
Claims	CLM	Y	N
Cooperative Patent Classification	CPC	Y	Y
Data Entry Date	DED	Y	Y
Data Update Date	DUPD	Y	Y
Detailed Description	DETD	Y (3)	N
Document Type	DT	Y	Y
Entry Date	ED	Y	Y
Entry Date Full Text	EDTX	Y	Y
European Patent Classification	EPC	Y	Y
Field Availability	FA	Y	N
Graphic Image, Size	GIS	Y	Y
Graphic Image, Type	GIT	Y	N
International Patent Classification	IC	Y	N
Inventor	IN (AU)	Y	Y
Inventor, Country	IN.CNY	Y	Y
ICO (in-computer-only) Classification	ICO	Y	Y
IPC (ICM, ICS, IPCI, IPCR)	IPC	Y	Y
IPC, Advanced Level Symbols	IPC.A	Y (4)	N
IPC, Advanced Level Symbols for Invention	IPC.AI	Y (4)	N
IPC, Initial	IPCI	Y	Y
IPC, Main	ICM	Y	Y
IPC, Reclassified	IPCR	Y	Y
IPC, Reform	IPC.REF	Y	N
IPC, Secondary	ICS	Y	Y
Language	LA	Y	Y
Language of Filing	LAF	Y	Y
Main Claim	MCLM	Y	N
Number of Claims	CLMN	Y	Y
Number of Paragraphs in DETD	DETN	Y	Y
Occurrence Count of Hit Terms	OCC	N	Y
Patent Assignee/Patentee	PA (CS)	Y	Y
Patent Assignee, Country	PA.CNY	Y	Y
Patent Assignee, Address	PAA	Y	N
Patent Assignee Number	PAN	Y	Y
Patent Country	PC	Y	Y
Patent Information Publication Type	PIT	Y	Y
Patent Kind Code	PK	Y	Y
Patent Number	PI (PN, PATS)	Y	Y
Patent Number, Original	PNO	Y	Y
Patent Number/Kind Code	PNK	Y	Y
Pre-IPC8 Symbols from the ICM and first IPC8 values from 2006-present	IPC.F	Y (4)	Y
Priority Country	PRC	Y	Y
Priority Date	PRD	Y	Y

SELECT, ANALYZE, and SORT Fields cont'd)

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Priority Date, First	PRDF	Y	Y
Priority Number	PRN (PRAI)	Y	Y
Priority Number, Original	PRNO	Y	Y
Priority Year	PRY	Y	Y
Priority Year, First	PRYF	Y	Y
Publication Date	PD	Y	Y
Publication Year	PY	Y	Y
Related Patent Country	RLC	Y	Y
Related Application Number	RLN	Y	Y
Related Application Date	RLD	Y	Y
Related Application Year	RLY	Y	Y
Title	TI	Y (default)	Y
Update Date	UP	Y	Y

(1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT TI.

(2) Selects or analyzes application numbers with /AP appended to the terms created by SELECT.

(3) Appends /BI to the terms created by SELECT.

(4) Appends /IPC to the terms created by SELECT.

Sample Records**DISPLAY ALL (STN format)**

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AN      2011019599  INFULL  ED 20130525  UP 20130525  EDTX 20130525
        DED 20120817  DUPD 20130417
TI      A COATING FOR PREPARING A GAS DIFFUSION LAYER AND A GAS DIFFUSION LAYER
        THEREOF
IN      ALKESH AHIRE; DR. NAWAL KISHOR MAL; DR. RAJIV KUMAR
PA      TATA CHEMICALS LIMITED, BOMBAY HOUSE, 24 HOMI MODI STREET, MUMBAI-400001
        Maharashtra India
LAF     English
DT      Patent; (Fulltext)
PIT     INA APPLICATION
PI      IN 2011MU00095          A      20120817
AI      IN 2011-MU95           20110111
PRAI   IN 2011-MU95           20110111
IPCI    H01M0008-00 [C]
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AB

Original

An electrode for a fuel cell is disclosed. The electrode comprises of a gas diffusion layer having an electrode catalyst layer coated thereon. The electrode catalyst layer comprises of a carbon supported catalyst. The carbon supported catalyst comprises of carbon supported platinum nanoparticles having at least one mercapto alkyl acid selected from the group comprising of mercatopropyl sulfonic acid, mercapto propionic acid and mercapto succinic acid, attached thereon.

DETD

The disclosure generally relates to an electrode for a fuel cell. More particularly, the disclosure relates to an electrode comprising a gas diffusion layer having a catalyst layer coated thereon.

BACKGROUND Fuel cells are power generation systems that convert chemical energy into electrical energy by oxidation of fuel. Fuel cells have a higher efficiency compared to internal combustion engines and are environment friendly. Therefore, fuel cells have become the focus of attention for researchers as an alternative energy source for fossil fuels.

One type of electrochemical fuel cell is the polymer electrolyte membrane (PEM) fuel cell, which employs a membrane electrode assembly (MEA)

INFULL

comprising of a proton conductive membrane which has cathode catalyst layer on one side and anode catalyst layer on the other side, sandwiched between two gas diffusion layers. Gas diffusion layers serve as current collectors that allow ready access of the fuel and oxidant to anode and cathode catalyst surfaces, respectively.

CLM

An electrode for a fuel cell comprising: a gas diffusion layer having an electrode catalyst layer coated thereon, wherein the electrode catalyst layer comprises of a carbon supported catalyst, the carbon supported catalyst comprising carbon supported platinum nanoparticles having at least one mercapto alkyl acid selected from the group comprising of mercaptopropyl sulfonic acid, mercapto propionic acid and mercapto succinic acid, attached thereon.

2. An electrode for a fuel cell as claimed in claim 1 wherein the carbon supported catalyst further comprises at least one alkyl thiol selected from the group comprising of hexane thiol, octane thiol, decane thiol and dodecane thiol attached to the platinum nanoparticles.

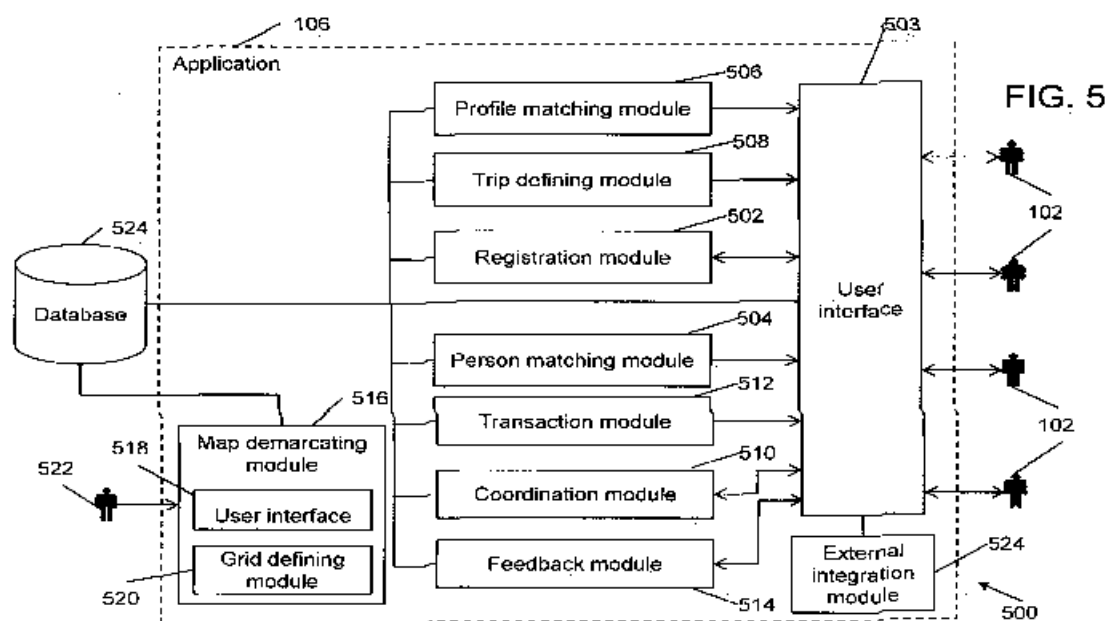
DISPLAY ISTD.M

ACCESSION NUMBER: 1997001337 INFULL
 ENTRY DATE: 20130301
 UPDATE DATE: 20130308
 ENTRY DATE (FULLTEXT): 20130301
 DATA ENTRY DATE: 20100220
 DATA UPDATE DATE: 20100220
 TITLE (ENGLISH): THE PROCESS FOR COMBINING ORGANISMS WITH ANTI INFECTIVE AGENT IN TO A FORMULATION
 PATENT APPLICANT(S): DR. RAJIV INDRAVANDAN MODI;
 LANGUAGE OF FILING: English
 LANGUAGE OF PUBL.: English
 DOCUMENT TYPE: Patent; (Fulltext)
 PATENT INFORMATION TYPE: INA APPLICATION
 PATENT INFORMATION: IN 1997MU00174 A 19971122
 APPLICATION INFO.: IN 1997-MU174 19970327
 PRIORITY INFO.: IN 1997-MU174 19970327

ACCESSION NUMBER: 1997001337 INFULL
 ENTRY DATE: 20130301
 UPDATE DATE: 20130308
 ENTRY DATE (FULLTEXT): 20130301
 DATA UPDATE DATE: 20130205
 TITLE (ENGLISH): The process for the preparation of a stable fixed dose pharmaceutical composition of anti infective agent/agents and micro organisms as active ingredients
 INVENTOR(S): MODI RAJIV INDRAVADAN DR, IN; BANSAL YATISH KUMAR DR, IN; KHAMAR MAFATLAL BAKULESH DR, IN
 PATENT APPLICANT(S): MODI RAJIV INDRAVADAN DR, IN; BANSAL YATISH KUMAR DR, IN; KHAMAR BAKULESH MAFATLAL DR, IN;
 LANGUAGE OF FILING: English
 LANGUAGE OF PUBL.: English
 DOCUMENT TYPE: Patent; (Fulltext)
 PATENT INFORMATION TYPE: INA1 PATENT
 PATENT INFORMATION: IN 183097 A1 19990904
 APPLICATION INFO.: IN 1997-MU174 19970327
 PRIORITY INFO.: IN 1997-MU174 19970327
 INT. PATENT CLASSIF.:
 MAIN: A61K035-66 (6)
 IPC RECLASSIF.: A61K0009-00 [I,A]; A61K0009-24 [I,A]; A61K0009-28 [N,A]; A61K0009-48 [I,A]; A61K0009-50 [N,A]; A61K0035-74 [I,A]
 CPC CLASSIF. A61K0009-209; A61K0009-0095; A61K0031-00; A61K0009-4808; A61K0009-5047; A61K0045-06; A61K0035-742; A61K0036-064; A61K0035-744; A61K0009-2866; A61K0035-747
 EPC CLASSIF. (ECLA): A61K0009-00Z6; A61K0009-20K4B; A61K0009-48A; A61K0035-74A1; A61K0035-74A2; A61K0035-74A2B
 IN-COMPUTER-ONLY CLASSIF.: K61K0009-28H6F2; K61K0009-50H6F2B

DISPLAY STDG.M

AN 2013000134 INFULL ED 20130525 UP 20130525
 DED 20130405 DUPD 20130517
 TI METHOD FOR COMMUTING IN AN AREA
 IN KHANNA, SAMEER; SAHAI, SWATI; BHAT, PROMILA
 PA KHANNA, SAMEER, D2/2125, VASANT KUNJ, NEW DELHI-110070, IN; SAHAI, SWATI;
 BHAT, PROMILA
 LAF English
 DT Patent
 PIT INA APPLICATION
 PI IN 2013DE00234 A 20130405
 AI IN 2013-DE234 20130129
 PRAI IN 2013-DE234 20130129
 IPCI G01C [C]



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